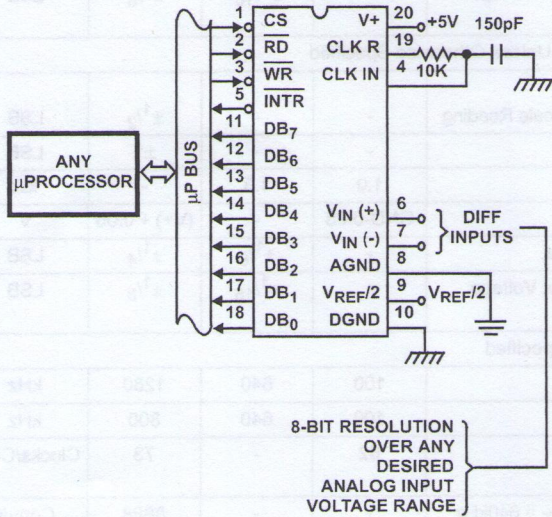


8-Bit, Microprocessor-Compatible, A/D Converters

The ADC080X family are CMOS 8-Bit, successive-approximation A/D converters which use a modified potentiometric ladder and are designed to operate with the 8080A control bus via three-state outputs. These converters appear to the processor as memory locations or I/O ports, and hence no interfacing logic is required.

The differential analog voltage input has good common-mode-rejection and permits offsetting the analog zero-input-voltage value. In addition, the voltage reference input can be adjusted to allow encoding any smaller analog voltage span to the full 8 bits of resolution.

Typical Application Schematic

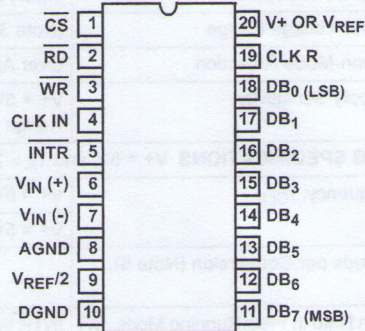


Features

- 80C48 and 80C80/85 Bus Compatible - No Interfacing Logic Required
- Conversion Time <100µs
- Easy Interface to Most Microprocessors
- Will Operate in a "Stand Alone" Mode
- Differential Analog Voltage Inputs
- Works with Bandgap Voltage References
- TTL Compatible Inputs and Outputs
- On-Chip Clock Generator
- Analog Voltage Input Range (Single + 5V Supply) 0V to 5V
- No Zero-Adjust Required
- 80C48 and 80C80/85 Bus Compatible - No Interfacing Logic Required

Pinout

ADC0803, ADC0804 (PDIP) TOP VIEW



Ordering Information

PART NUMBER	ERROR	EXTERNAL CONDITIONS	TEMP. RANGE (°C)	PACKAGE	PKG. NO
ADC0803LCN	±1/2 LSB	V _{REF/2} Adjusted for Correct Full Scale Reading	0 to 70	20 Ld PDIP	E20.3
ADC0804LCN	±1 LSB	V _{REF/2} = 2.500V _{DC} (No Adjustments)	0 to 70	20 Ld PDIP	E20.3

ADC0803, ADC0804

Absolute Maximum Ratings

Supply Voltage 6.5V
 Voltage at Any Input -0.3V to (V⁺ +0.3V)

Operating Conditions

Temperature Range 0°C to 70°C

Thermal Information

Thermal Resistance (Typical, Note 1) θ_{JA} (°C/W)
 PDIP Package 80
 Maximum Junction Temperature
 Plastic Package 150°C
 Maximum Storage Temperature Range -65°C to 150°C
 Maximum Lead Temperature (Soldering, 10s) 300°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. θ_{JA} is measured with the component mounted on a low effective thermal conductivity test board in free air. See Tech Brief TB379 for details.

Electrical Specifications (Notes 2, 8)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
CONVERTER SPECIFICATIONS V ⁺ = 5V, T _A = 25°C and f _{CLK} = 640kHz, Unless Otherwise Specified					
Total Unadjusted Error					
ADC0803	V _{REF/2} Adjusted for Correct Full Scale Reading	-	-	±1/2	LSB
ADC0804	V _{REF/2} = 2.500V	-	-	±1	LSB
V _{REF/2} Input Resistance	Input Resistance at Pin 9	1.0	1.3	-	kΩ
Analog Input Voltage Range	(Note 3)	GND-0.05	-	(V ⁺) + 0.05	V
DC Common-Mode Rejection	Over Analog Input Voltage Range	-	±1/16	±1/8	LSB
Power Supply Sensitivity	V ⁺ = 5V ±10% Over Allowed Input Voltage Range	-	±1/16	±1/8	LSB
CONVERTER SPECIFICATIONS V ⁺ = 5V, 0°C to 70°C and f _{CLK} = 640kHz, Unless Otherwise Specified					
Total Unadjusted Error					
ADC0803	V _{REF/2} Adjusted for Correct Full Scale Reading	-	-	±1/2	LSB
ADC0804	V _{REF/2} = 2.500V	-	-	±1	LSB
V _{REF/2} Input Resistance	Input Resistance at Pin 9	1.0	1.3	-	kΩ
Analog Input Voltage Range	(Note 3)	GND-0.05	-	(V ⁺) + 0.05	V
DC Common-Mode Rejection	Over Analog Input Voltage Range	-	±1/8	±1/4	LSB
Power Supply Sensitivity	V ⁺ = 5V ±10% Over Allowed Input Voltage Range	-	±1/16	±1/8	LSB
AC TIMING SPECIFICATIONS V ⁺ = 5V, and T _A = 25°C, Unless Otherwise Specified					
Clock Frequency, f _{CLK}	V ⁺ = 6V (Note 4)	100	640	1280	kHz
	V ⁺ = 5V	100	640	800	kHz
Clock Periods per Conversion (Note 5), t _{CONV}		62	-	73	Clocks/Conv
Conversion Rate In Free-Running Mode, CR	INTR tied to WR with CS = 0V, f _{CLK} = 640kHz	-	-	8888	Conv/s
Width of WR Input (Start Pulse Width), t _{W(WR)}	CS = 0V (Note 6)	100	-	-	ns
Access Time (Delay from Falling Edge of RD to Output Data Valid), t _{ACC}	C _L = 100pF (Use Bus Driver IC for Larger C _L)	-	135	200	ns
Three-State Control (Delay from Rising Edge of RD to HI-Z State), t _{1H} , t _{0H}	C _L = 10pF, R _L = 10K (See Three-State Test Circuits)	-	125	250	ns
Delay from Falling Edge of WR to Reset of INTR, t _{WI} , t _{RI}		-	300	450	ns
Input Capacitance of Logic Control Inputs, C _{IN}		-	5	-	pF
Three-State Output Capacitance (Data Buffers), C _{OUT}		-	5	-	pF

2/3

Electrical Specifications (Notes 2, 8) (Continued)

PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNITS
DC DIGITAL LEVELS AND DC SPECIFICATIONS $V+ = 5V$, and T_{MIN} to T_{MAX} , Unless Otherwise Specified					
CONTROL INPUTS (Note 7)					
Logic "1" Input Voltage (Except Pin 4 CLK IN), V_{INH}	$V+ = 5.25V$	2.0	-	$V+$	V
Logic "0" Input Voltage (Except Pin 4 CLK IN), V_{INL}	$V+ = 4.75V$	-	-	0.8	V
CLK IN (Pin 4) Positive Going Threshold Voltage, V^{+}_{CLK}		2.7	3.1	3.5	V
CLK IN (Pin 4) Negative Going Threshold Voltage, V^{-}_{CLK}		1.5	1.8	2.1	V
CLK IN (Pin 4) Hysteresis, V_H		0.6	1.3	2.0	V
Logic "1" Input Current (All Inputs), I_{INH}	$V_{IN} = 5V$	-	0.005	1	μA
Logic "0" Input Current (All Inputs), I_{INL}	$V_{IN} = 0V$	-1	-0.005	-	μA
Supply Current (Includes Ladder Current), $I+$	$f_{CLK} = 640kHz$, $T_A = 25^{\circ}C$ and $\overline{CS} = HI$	-	1.3	2.5	mA
DATA OUTPUTS AND INTR					
Logic "0" Output Voltage, V_{OL}	$I_O = 1.6mA$, $V+ = 4.75V$	-	-	0.4	V
Logic "1" Output Voltage, V_{OH}	$I_O = -360\mu A$, $V+ = 4.75V$	2.4	-	-	V
Three-State Disabled Output Leakage (All Data Buffers), I_{LO}	$V_{OUT} = 0V$	-3	-	-	μA
	$V_{OUT} = 5V$	-	-	3	μA
Output Short Circuit Current, I_{SOURCE}	V_{OUT} Short to GND, $T_A = 25^{\circ}C$	4.5	6	-	mA
Output Short Circuit Current, I_{SINK}	V_{OUT} Short to $V+$, $T_A = 25^{\circ}C$	9.0	16	-	mA

NOTES:

- All voltages are measured with respect to GND, unless otherwise specified. The separate AGND point should always be wired to the DGND, being careful to avoid ground loops.
- For $V_{IN(-)} \geq V_{IN(+)}$ the digital output code will be 0000 0000. Two on-chip diodes are tied to each analog input (see Block Diagram) which will forward conduct for analog input voltages one diode drop below ground or one diode drop greater than the $V+$ supply. Be careful, during testing at low $V+$ levels (4.5V), as high level analog inputs (5V) can cause this input diode to conduct - especially at elevated temperatures, and cause errors for analog inputs near full scale. As long as the analog V_{IN} does not exceed the supply voltage by more than 50mV, the output code will be correct. To achieve an absolute 0V to 5V input voltage range will therefore require a minimum supply voltage of 4.950V over temperature variations, initial tolerance and loading.
- With $V+ = 6V$, the digital logic interfaces are no longer TTL compatible.
- With an asynchronous start pulse, up to 8 clock periods may be required before the internal clock phases are proper to start the conversion process.
- The \overline{CS} input is assumed to bracket the \overline{WR} strobe input so that timing is dependent on the \overline{WR} pulse width. An arbitrarily wide pulse width will hold the converter in a reset mode and the start of conversion is initiated by the low to high transition of the \overline{WR} pulse (see Timing Diagrams).
- CLK IN (pin 4) is the input of a Schmitt trigger circuit and is therefore specified separately.
- None of these A/Ds requires a zero-adjust. However, if an all zero code is desired for an analog input other than 0V, or if a narrow full scale span exists (for example: 0.5V to 4V full scale) the $V_{IN(-)}$ input can be adjusted to achieve this. See the Zero Error description in this data sheet.

Timing Waveforms

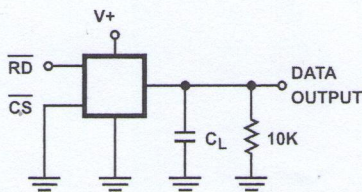


FIGURE 1A. t_{1H}

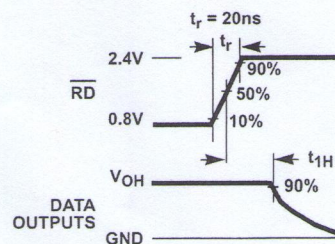


FIGURE 1B. t_{1H} , $C_L = 10pF$

313